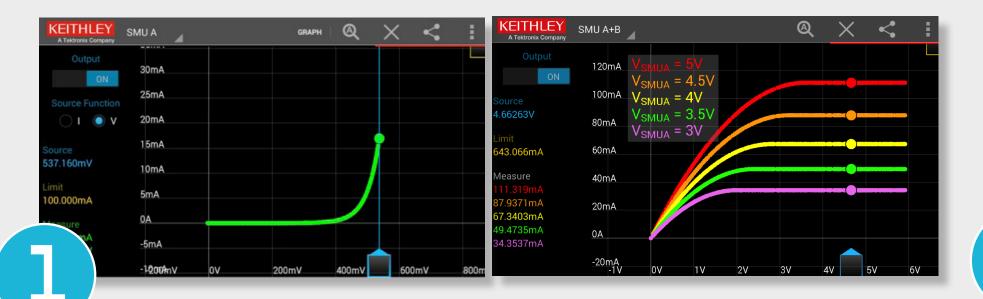
Tektronix[®]

7 KEYS TO DETECTING POTENTIAL DUT ISSUES

Minimize Troubleshooting Time and Boost Productivity

Perform these seven easy tests on your battery, diode, LED, FET, or other device under test (DUT) to identify potential issues early, avoid extensive troubleshooting, and have confidence that the DUT is suitable for use in your circuit.



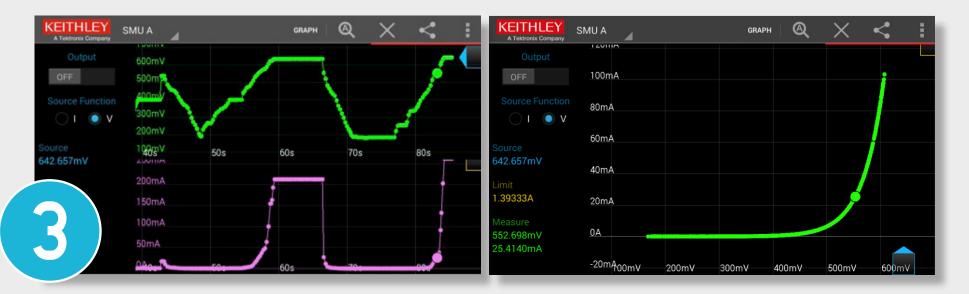
I-V Characterization with Real-time Control

Typical I-V characterization requires writing programs or configuring test software to source voltage or current in a certain range and then query the instrument for measurement. In most cases, measurements are displayed or plotted after your run the test program. But, real-time control eliminates this delayed visualization and allows you to adjust test parameters as you go, providing you with instant insight into your DUT.



Monitor I-V Trends over Time

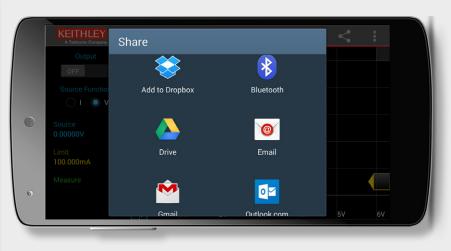
It's especially important to monitor device behavior over time to identify DUT problems that occur with changes in ambient conditions, such as temperature, lighting and device self-heating. Keithley IVy provides a time mode to monitor your devices.



Understand Measurement Results from Different Perspectives

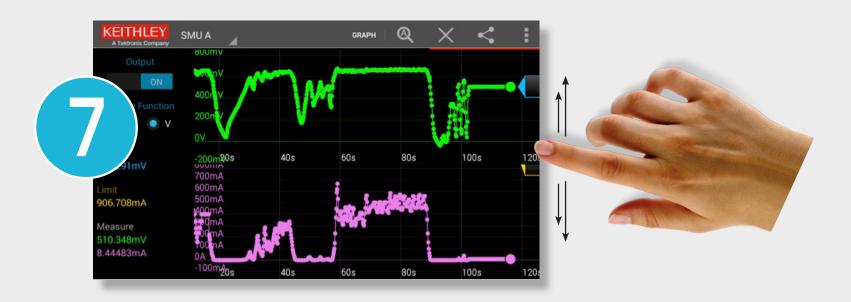
Having trouble determining the reason behind a particular anomaly in your measurements? Measurement data makes more sense when you look at it from different perspectives. Use IVy to change seamlessly between I-V vs. time and I vs. V display modes to explore peculiarities in device behavior.

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Share Measurement Results for Collaborative Work

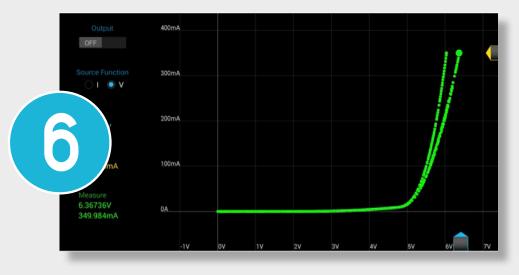
Show a colleague your data by sharing a data plot or a CSV file.





Zoom into Your Measurement to See the Details

Is the above diode characterization normal? Zoom in to look at it more carefully before you say yes.



Compare Your Device to a "Golden Device"

Stimulus-Response Behavior over Time

Have you tested your component's stimulus-response behavior? The test results may surprise you! You can change source value in real time to see the DUT response instantly.

A golden device is a known-good device that is often used when testing components. Compare test results of an unknown device against a standardized, known-good device to determine if it is operating correctly. Plot multiple curves on one screen, which makes comparison easier.

The Keithley IVy App lets you perform these tests on your DUT in seconds with just the touch of a finger.

Get the Keithley IVy App Now!





Use IVy with any Keithley Series 2600B SourceMeter[®] SMU Instrument. Visit <u>www.keithley.com/2600B</u> to learn more.

